

<b>Notice of References Cited</b>	Application/Control No. 10/626,552	Applicant(s)/Patent Under Reexamination YAMAI ET AL.	
	Examiner Jennifer A. Leung	Art Unit 1764	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,528,130	07-1985	Ledebrink et al.	252/643
	B	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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